

STP40NF10L

N-channel 100V - 0.028Ω - 40A TO-220 Low gate charge STripFET™ Power MOSFET

General features

Туре	V _{DSS}	R _{DS(on)}	۱ _D
STP40NF10L	100V	<0.033Ω	40A

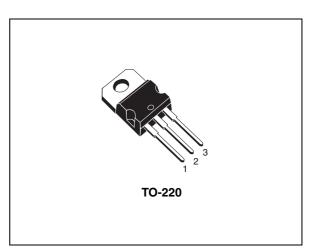
- Exceptional dv/dt capability
- 100% avalanche tested
- Application oriented characterization

Description

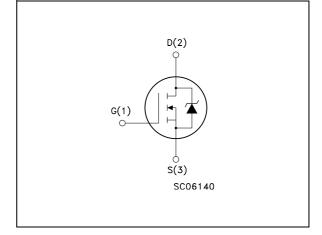
This Power MOSFET series realized with STMicroelectronics unique STripFET process has specifically been designed to minimize input capacitance and gate charge. It is therefore suitable as primary switch in advanced highefficiency isolated DC-DC converters for Telecom and Computer application. It is also intended for any application with low gate charge drive requirements.

Applications

Switching application



Internal schematic diagram



Order codes

Part number	Marking	Package	Packaging
STP40NF10L	P40NF10L	TO-220	Tube

January	2007
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Electrical ratings

Table 1.	Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{DS}	Drain-source voltage (v _{gs} = 0)	100	V
V _{GS}	Gate- source voltage	±17	V
I _D	Drain current (continuous) at $T_C = 25^{\circ}C$	40	А
I _D	Drain current (continuous) at $T_C = 100^{\circ}C$	25	А
I _{DM} ⁽¹⁾	Drain current (pulsed)	160	А
P _{TOT}	Total dissipation at $T_{C} = 25^{\circ}C$	150	W
	Derating factor	1	W/°C
E _{AS} ⁽²⁾	Single pulse avalanche energy	430	mJ
T _{stg}	Storage temperature	– 65 to 175	J°
Тj	Max. operating junction temperature	175	0

1. Pulse width limited by safe operating area

2. Starting T_j = 25°C, I_D = 20A, V_{DD} =40V

Table 2. Thermal data

R _{thj-case}	Thermal resistance junction-case Max	1	°C/W
R _{thj-a}	Thermal resistance junction-ambient Max	62.5	°C/W
т	Maximum lead temperature for soldering purpose	300	°C



2 Electrical characteristics

(T_{CASE} =25°C unless otherwise specified)

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
V _{(BR)DSS}	Drain-source Breakdown voltage	$I_{D} = 250 \ \mu A, \ V_{GS} = 0$	100			V
I _{DSS}	Zero gate voltage Drain current (V _{GS} = 0)	V _{DS} = Max rating V _{DS} =Max rating, T _C =125°C			1 10	μΑ μΑ
I _{GSS}	Gate-body leakage current (V _{DS} = 0)	$V_{GS} = \pm 17V$			±100	nA
V _{GS(th)}	Gate threshold voltage	$V_{DS} = V_{GS}, I_D = 250 \mu A$	1	1.7	2.5	V
R _{DS(on)}	Static drain-source on resistance	$V_{GS} = 10V$, $I_D = 20A$ $V_{GS} = 5V$, $I_D = 20A$		0.028 0.030	0.033 0.036	Ω Ω

Table 3. On/off states

Table 4. Dynamic

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
g _{fs} ⁽¹⁾	Forward transconductance	V _{DS} = 15V _, I _D =20A		25		S
C _{iss}	Input capacitance			2300		pF
C _{oss}	Output capacitance	V _{DS} = 25V, f = 1 MHz, V _{GS} = 0		290		pF
C _{rss}	Reverse transfer capacitance	V _{GS} = 0		125		pF
Qg	Total gate charge			46	64	nC
Q _{gs}	Gate-source charge	$V_{DD} = 80V, I_D = 40A,$ $V_{GS} = 5V$		12		nC
Q _{gd}	Gate-drain charge	VGS - UV		22		nC

1. Pulsed: Pulse duration = $300 \ \mu$ s, duty cycle 1.5.

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
t _{d(on)} t _r	Turn-on delay time Rise time	$\label{eq:VDD} \begin{split} V_{DD} &= 50 V, \ I_D = 20 A \\ R_G &= 4.7 \Omega \ V_{GS} = 4.5 V \\ (see \ Figure \ 13) \end{split}$		25 82		ns ns
t _{d(off)} t _f	Turn-off-delay time Fall time	$V_{DD} = 50V, I_D = 20A,$ $R_G = 4.7\Omega, V_{GS} = 4.5V$ (see Figure 13)		64 24		ns ns
t _{d(off)} t _f t _c	Off-voltage Rise Time Fall Time Cross-over time	$\label{eq:Vclamp} \begin{array}{l} \mbox{Vclamp} = \mbox{80V}, \ \mbox{I}_D = \mbox{40 A} \\ \mbox{R}_G = \mbox{4.5V} \\ \mbox{(see Figure 15)} \end{array}$		51 29 53		ns ns ns

Table 5. Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max	Unit
I _{SD}	Source-drain current				40	Α
$I_{SDM}^{(1)}$	Source-drain current (pulsed)				160	А
$V_{SD}^{(2)}$	Forward on voltage	$I_{SD} = 40A, V_{GS} = 0$			1.3	V
t _{rr} Q _{rr} I _{RRM}	Reverse recovery time Reverse recovery charge Reverse recovery current	$I_{SD} = 40A, V_{DD} = 30V$ di/dt = 100A/µs, T _j = 150°C (see Figure 15)		110 467 8		ns nC A

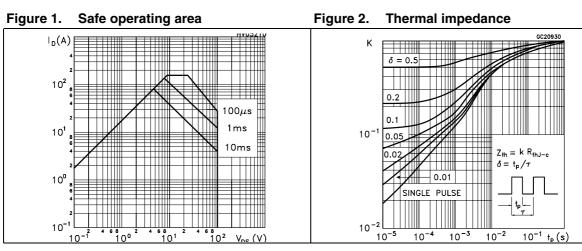
Table 6. Source drain diode

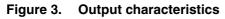
1. Pulse width limited by safe operating area.

2. Pulsed: Pulse duration = 300 μ s, duty cycle 1.5%



Electrical characteristics (curves) 2.1





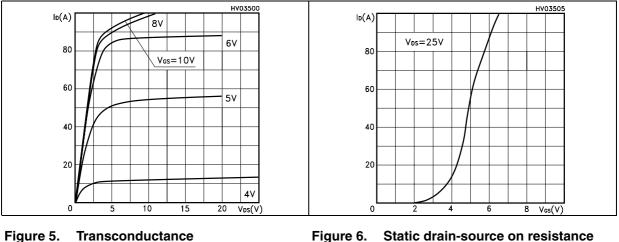
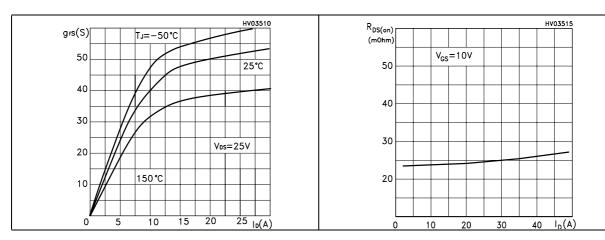


Figure 4.

Transfer characteristics





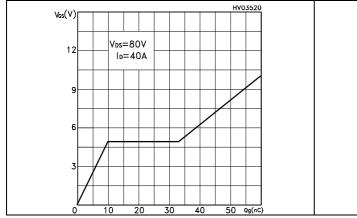


Figure 7. Gate charge vs. gate-source voltage Figure 8. Capacitance variations

Figure 9. Normalized gate threshold voltage vs. temperature

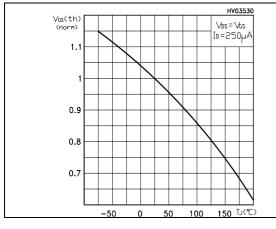


Figure 11. Source-drain diode forward characteristics

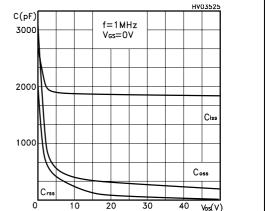


Figure 10. Normalized on resistance vs. temperature

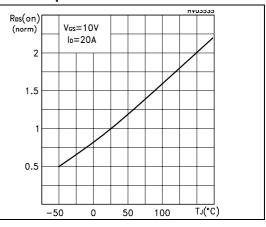
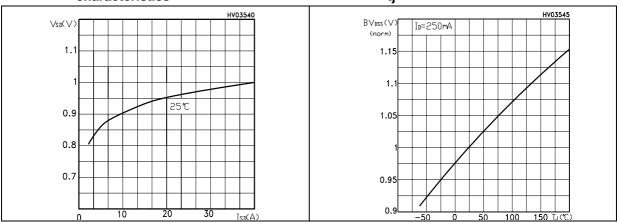
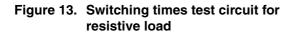


Figure 12. Normalized breakdown voltage vs. tj



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3 Test circuit



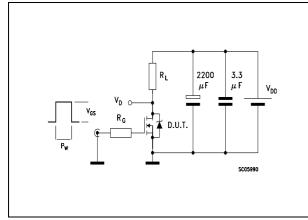
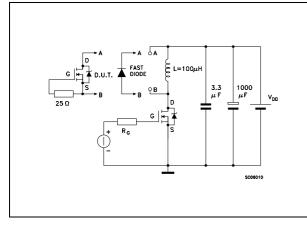
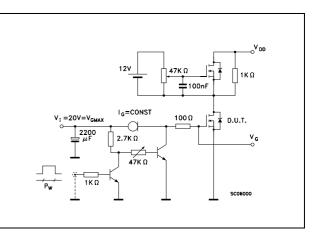
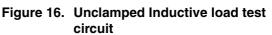


Figure 15. Test circuit for inductive load switching and diode recovery times









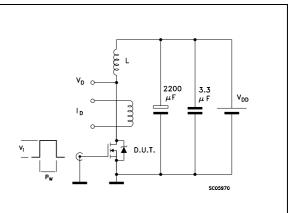


Figure 18. Switching time waveform

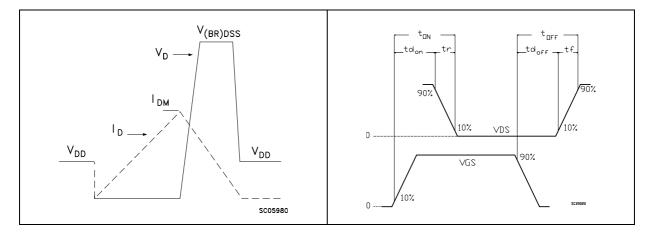


Figure 14. Gate charge test circuit

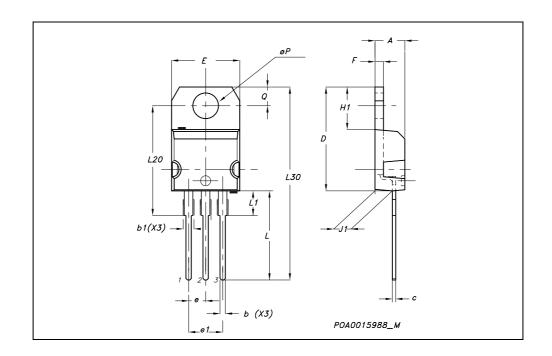
4 Package mechanical data

In order to meet environmental requirements, ST offers these devices in ECOPACK® packages. These packages have a Lead-free second level interconnect. The category of second level interconnect is marked on the package and on the inner box label, in compliance with JEDEC Standard JESD97. The maximum ratings related to soldering conditions are also marked on the inner box label. ECOPACK is an ST trademark. ECOPACK specifications are available at : *www.st.com*



DIM.		mm.			inch	
DIM.	MIN.	ТҮР	MAX.	MIN.	TYP.	MAX.
А	4.40		4.60	0.173		0.181
b	0.61		0.88	0.024		0.034
b1	1.15		1.70	0.045		0.066
С	0.49		0.70	0.019		0.027
D	15.25		15.75	0.60		0.620
E	10		10.40	0.393		0.409
е	2.40		2.70	0.094		0.106
e1	4.95		5.15	0.194		0.202
F	1.23		1.32	0.048		0.052
H1	6.20		6.60	0.244		0.256
J1	2.40		2.72	0.094		0.107
L	13		14	0.511		0.551
L1	3.50		3.93	0.137		0.154
L20		16.40			0.645	
L30		28.90			1.137	
øР	3.75		3.85	0.147		0.151
Q	2.65		2.95	0.104		0.116

TO-220 MECHANICAL DATA



5 Revision history

Date	Revision	Changes
09-Sep-2004	1	First version.
17-Aug-2006	2	The document has been reformatted.
31-Jan-2007	3	Typo mistake on Table 1.



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